

<b>Notice of References Cited</b>	Application/Control No. 10/711,772		Applicant(s)/Patent Under Reexamination CHARYTAN ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0116028	06-2005	Cohen et al.	235/380
*	B	US-2005/0123112	06-2005	New et al.	379/114.2
*	C	US-2005/0008132	01-2005	Paschini et al.	379/093.12
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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